

XPS coupled with GCIB depth profiling

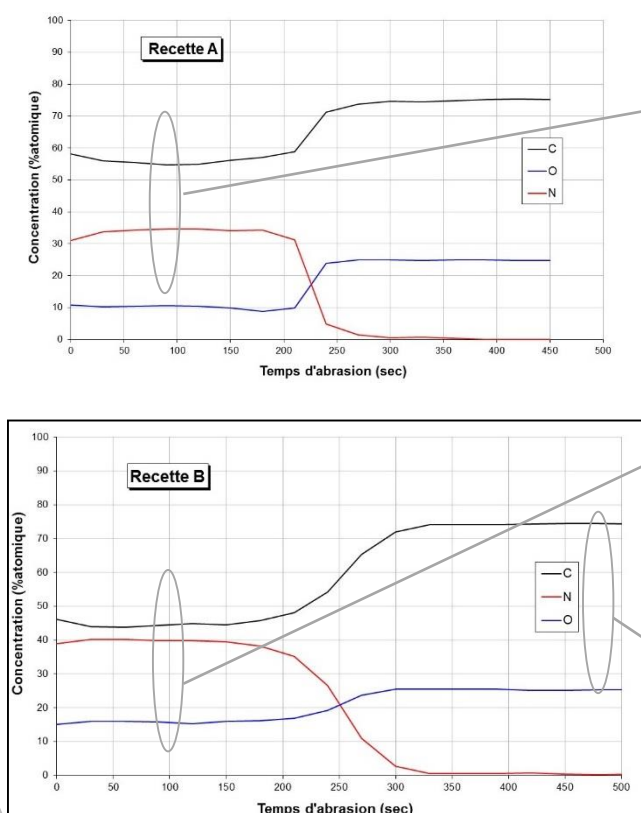
Subject : Identification, separation of nanolayers and multilayers obtained by atmospheric plasma on PET films

Techniques: XPS + GCIB

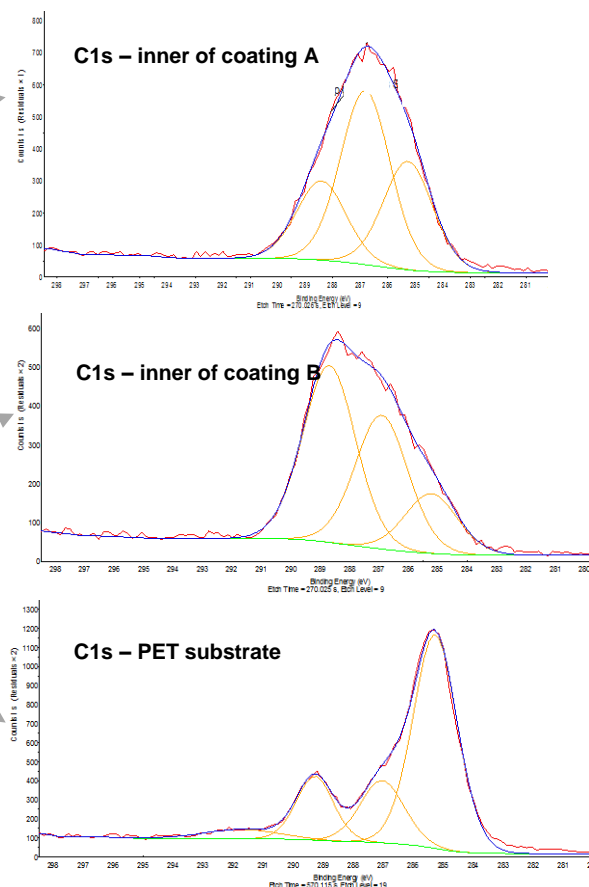
- ✓ GCIB : Gas Clusters Ion Beam
- ✓ Quantitative depth profiling of organic layers in order to study their inner chemical environment

Results:

1. Quantitative depth profiles



2. Carbon chemical environment



Conclusion:

Use of an argon clusters source for depth profiling on polymer coatings without damage, allowing quantitative depth profiles at high in depth resolution and determination of inner chemical environment of nano-coatings.